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CRYSTAL OSCILLATORS, CLASS 2, 4MHz TO 100MHz, AHCMOS AND ACMOS COMPATIBLE OUTPUT, RAD-HARD

BASED ON TYPE RK135

ESCC Detail Specification No. 3503/001

Issue 5 February 2022





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ISSUE 5

DOCUMENTATION CHANGE NOTICE

(Refer to https://escies.org for ESCC DCR content)

DCR No.	CHANGE DESCRIPTION
1464	Specification upissued to incorporate changes per DCR



ESCC Detail Specification

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1 GENERAL

1.1 SCOPE

This specification details the ratings, physical and electrical characteristics and test and inspection data for the component type variants and/or the range of components specified below. It supplements the requirements of, and shall be read in conjunction with, the ESCC Generic Specification listed under Applicable Documents.

1.2 APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:

(a) ESCC Generic Specification No. 3503.

1.3 TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESCC Basic Specification No. 21300 shall apply.

1.4 THE ESCC COMPONENT NUMBER AND COMPONENT TYPE VARIANTS

1.4.1 The ESCC Component Number

The ESCC Component Number shall be constituted as follows:

Example: 350300101R100M000000HC

- Detail Specification Reference: 3503001
- Component Type Variant Number: 01 (as required)
- Total Dose Radiation Level Letter (100krad(Si)): R (as required)
- Characteristic code: Nominal Frequency (100MHz): 100M000000 (as required)
- Characteristic code: Output Waveform (AHCMOS): HC (as required)

1.4.2 <u>Characteristics Codes</u>

Characteristics to be codified as part of the ESCC Component Number shall be as follows:

(a) Nominal Frequency expressed by means of the following codes. The unit quantity shall be MHz:

Nominal Frequency f _{Nom} (MHz)	Code
X.XXXXXX	XMXXXXXX
XX.XXXXXX	XXMXXXXXX
XXX.XXXXX	XXXMXXXXXX

(b) Output Waveform type expressed by means of the following codes:

Output Waveform	Code
AHCMOS	HC
ACMOS	AC



1.4.3 <u>Component Type Variants</u>

The component type variants applicable to this specification are as follows:

Variant Number	Nominal Output Frequency f _{Nom} (MHz)	Case	Nominal Supply Voltage V _{CCNom} (V)	Output Waveform	Terminal Material and Finish	Weight max g	Total Dose Radiation Level Letter
01	4 to 100	FP1	3.3	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
02	4 to 100	FP2	3.3	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
03	4 to 100	FP3	3.3	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
04	4 to 100	FP4	3.3	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
05	4 to 100	DIL1	3.3	AHCMOS, ACMOS	G2	5	R [100krad(Si)]
06	4 to 100	JL2	3.3	AHCMOS, ACMOS	D2	2	R [100krad(Si)]
07	4 to 100	FP1	5	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
08	4 to 100	FP2	5	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
09	4 to 100	FP3	5	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
10	4 to 100	FP4	5	AHCMOS, ACMOS	D2	5	R [100krad(Si)]
11	4 to 100	DIL1	5	AHCMOS, ACMOS	G2	5	R [100krad(Si)]
12	4 to 100	JL2	5	AHCMOS, ACMOS	D2	2	R [100krad(Si)]

The terminal material and finish shall be in accordance with the requirements of ESCC Basic Specification No. 23500.

Total dose radiation level letters are defined in ESCC Basic Specification No. 22900. If an alternative radiation test level is specified in the Purchase Order the letter shall be changed accordingly.



1.5 <u>MAXIMUM RATINGS</u>

The maximum ratings shall not be exceeded at any time during use or storage.

Maximum ratings shall only be exceeded during testing to the extent specified in this specification and when stipulated in Test Methods and Procedures of the ESCC Generic Specification.

Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Supply Voltage	Vcc	-0.5 to +7	V	Note 1
Load Impedance	CL	50	рF	Note 2
Operating Temperature Range	Тор	-55 to +110	°C	T _{amb}
Storage Temperature Range	T _{stg}	-55 to +110	°C	
Soldering Temperature	T _{sol}	+260	°C	Note 3

NOTES:

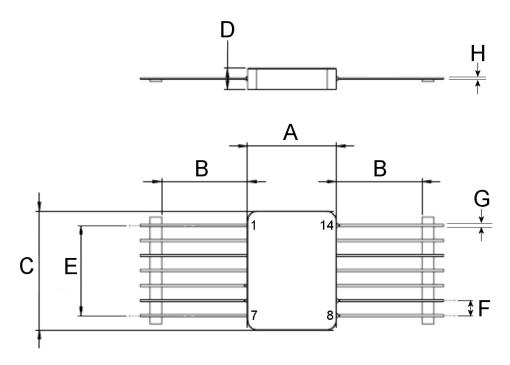
- 1. Device is functional as follows:
 - Variants 01 to 06: $+2.97V \le V_{CC} \le +3.63V$ (where nominal V_{CC} , $V_{CCNom} = +3.3V$)
 - Variants 07 to 12: $\pm 4.5 \text{V} \leq \text{V}_{CC} \leq \pm 5.5 \text{V}$ (where nominal V_{CC} , $\text{V}_{CCNom} = \pm 5 \text{V}$)
- 2. Device is functional as follows:

Variant Number	Output Waveform	Frequency Range	Load Impedance
01 to 06	AHCMOS	4MHz ≤ f _{Nom} < 80MHz	C_{LMin} = 13pF \leq C_{L} \leq C_{LMax} = 18pF (load in parallel with R_{L} = 1k Ω) (where nominal C_{L} , C_{LNom} = 15pF)
		80MHz ≤ f _{Nom} ≤ 100MHz	C_{LMin} = 8.2pF \leq C_{L} \leq C_{LMax} = 11pF (load in parallel with R_{L} = 1k Ω) (where nominal C_{L} , C_{LNom} = 10pF)
07 to 12		4MHz ≤ f _{Nom} < 100MHz	C_{LMin} = 13pF \leq C_{L} \leq C_{LMax} = 18pF (load in parallel with R_{L} = 1k Ω)) (where nominal C_{L} , C_{LNom} = 15pF)
01 to 12	ACMOS	4MHz ≤ f _{Nom} < 100MHz	C_{LMin} = 13pF \leq C_{L} \leq C_{LMax} = 18pF (load in parallel with R_{L} = 1k Ω) (where nominal C_{L} , C_{LNom} = 15pF)

3. Hand soldering: duration 10 seconds maximum at a distance of not less than 1.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.

1.6 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION

1.6.1 Flat Package (FP1) – 14 leads



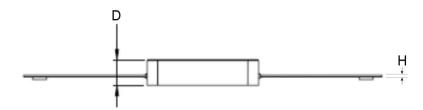
	Dimensi			
Symbols	Min	Max	Notes	
А	14.86	15.12		
В	14	15		
С	19.94	20.2		
D	-	3.71		
Е	15.24	15.24 BSC		
F	2.54	2.54 BSC		
G	0.28 0.48		All leads	
Н	0.15	0.35	All leads	

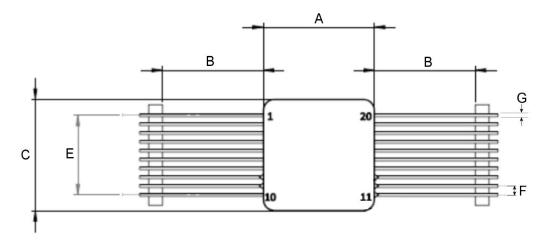
NOTES:

The terminal identification is specified by marking of the terminal number on the lid as shown. See Para. 1.7 for the terminal connections.



1.6.2 Flat Package (FP2) - 20 leads





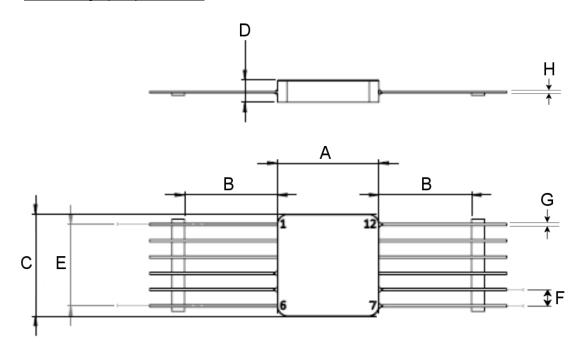
	Dimensi		
Symbols	Min	Max	Notes
Α	15.75	16.01	
В	14	15	
С	15.75 16.01		
D	-	3.83	
E	11.43	BSC	2 places
F	1.27	1.27 BSC	
G	0.28 0.48		All leads
Н	0.15	0.35	All leads

NOTES:

1. The terminal identification is specified by marking of the terminal number on the lid as shown. See Para. 1.7 for the terminal connections.



1.6.3 Flat Package (FP3) - 12 leads



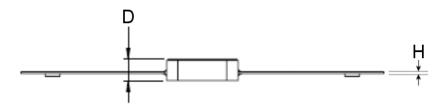
	Dimensi			
Symbols	Min	Max	Notes	
Α	15.75	16.01		
В	14	15		
С	15.75	16.01		
D	-	3.58		
Е	12.7	BSC	2 places	
F	2.54	All leads		
G	0.28	0.48	All leads	
Н	0.15	All leads		

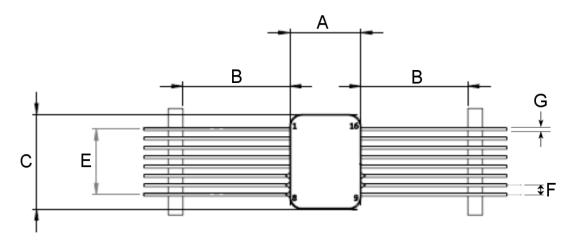
NOTES:

1. The terminal identification is specified by marking of the terminal number on the lid as shown. See Para. 1.7 for the terminal connections.

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1.6.4 Flat Package (FP4) - 16 leads



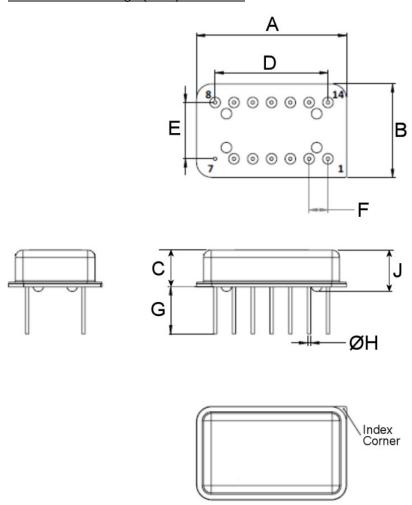


	Dimensions mm		
Symbols	Min	Max	Notes
А	-	9.66	
В	13.9	15.1	
С	-	12.83	
D	-	3.1	
Е	8.89	BSC	2 places
F	1.27 BSC		All leads
G	0.28 0.48		All leads
Н	0.15	0.35	All leads

NOTES:
The terminal identification is specified by marking of the terminal number on the lid as shown. See Para. 1.7 for the terminal connections.



1.6.5 <u>Dual-in-Line Package (DIL1) – 14 leads</u>



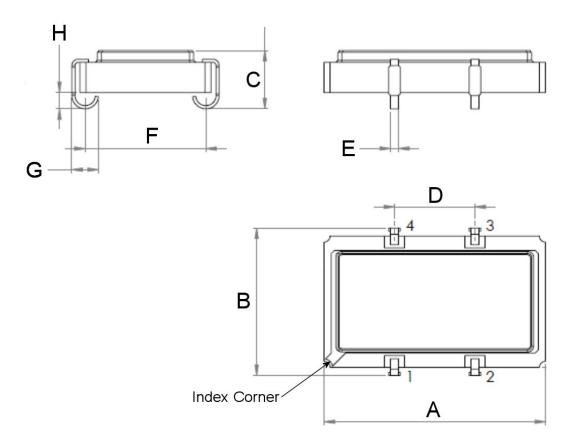
	Dimensi			
Symbols	Min	Max	Notes	
Α	-	20.7		
В	-	13.1		
С	-	5.45		
D	15.24	15.24 BSC		
Е	7.62	7.62 BSC		
F	2.54	BSC	All leads	
G	6.22	6.48	All leads	
ØH	0.25	0.65	All leads	
J	-	6	4 places	

NOTES:

The terminal identification is specified by reference to the index corner as shown. See Para. 1.7 for the terminal connections.



1.6.6 J-Lead Package (JL2) - 4 leads

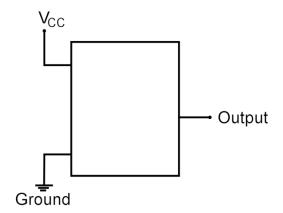


	Dimensi		
Symbols	Min	Max	Notes
Α	13.72	14.22	
В	8.8	9.8	2 places
С	-	4.2	All leads
D	4.93	5.23	2 places
Е	0.46	0.56	All leads
F	7.42	7.82	All leads
G	1.58	1.78	All leads
Н	0.89	1.15	All leads

NOTES: The terminal identification is specified by reference to the index corner as shown. See Para. 1.7 for the terminal connections.



1.7 <u>FUNCTIONAL DIAGRAM</u>



Variant	Case		Terminal Number				
Number		Output	Vcc	Ground	Not Connected		
01, 07	FP1	8	14	1, 2, 3, 4, 7, 10, 11, 12, 13	5, 6, 9	1, 2	
02, 08	FP2	11	13	1, 2, 3, 4, 5, 6, 7, 10, 14, 15, 16, 17, 18, 19, 20	8, 9, 12	1, 2	
03, 09	FP3	7	12	1, 2, 3, 6, 9, 10, 11	4, 5, 8	1, 2	
04, 10	FP4	10	8	1, 2, 3, 4, 5, 9, 12, 13, 14, 15, 16	6, 7, 11	1, 2	
05, 11	DIL1	8	14	7	1, 2, 3, 4, 5, 6, 9, 10, 11, 12, 13	1, 2	
06, 12	JL2	3	4	2	1	1, 2	

NOTES:

- The case is connected to Ground.
- 2. Not connected pins must be connected to a potential (e.g. Ground)

1.8 MATERIALS AND FINISHES

Materials and finishes shall be as follows:

(a) Case

The FP1, FP2, FP3, FP4 and DIL1 cases shall be hermetically sealed, and have a metal body with hard glass seals and a seam sealed metal lid.

The JL2 case shall be hermetically sealed, and have a ceramic body with brazed leads and a seam sealed lid.

(b) Terminals

As specified in Para. 1.4.3 Component Type Variants.



2 **REQUIREMENTS**

2.1 GENERAL

The complete requirements for procurement of the components specified herein are as stated in this specification and the ESCC Generic Specification. Permitted deviations from the Generic Specification, applicable to this specification only, are listed below.

Permitted deviations from the Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESCC requirement and do not affect the component's reliability, are listed in the appendices attached to this specification.

2.1.1 Oscillator Class

The components specified herein shall satisfy the requirements Class 2 Oscillators in accordance with the Generic Specification.

2.1.2 <u>Deviations from the Generic Specification</u>

2.1.2.1 Deviations from Qualification and Periodic Tests - Chart F4

- (a) Mechanical Shock: the following test conditions shall apply: MIL-STD-202, Test Method 213, Test Condition F except that the tests condition values shall be: 2000g, 0.3ms, half-sine.
- (b) Random Vibration: the following test conditions shall apply:
 MIL-STD-202, Test Method 214, Test Condition I-J (37.8grms overall), 3 minutes per axis.

2.2 MARKING

The marking shall be in accordance with the requirements of ESCC Basic Specification No. 21700 and as follows.

The information to be marked on the component shall be:

- (a) Terminal identification (see Para. 1.6).
- (b) The ESCC Qualified Component symbol (for ESCC qualified components only).
- (c) The ESCC Component Number (see Para. 1.4.1).
- (d) Traceability information.



2.3 <u>ELECTRICAL MEASUREMENTS AT ROOM, HIGH AND LOW TEMPERATURES</u> Electrical measurements shall be performed at room, high and low temperatures. Consolidated notes are given in Para. 2.3.3.

2.3.1 Room Temperature Electrical Measurements

Characteristics	Symbols	Test	Test Conditions	Lin	nits	Units
		Method	Note 1	Min	Max	
Input Current	lin	ESCC No. 24200	For $4MHz \le f_{Nom} < 20MHz$: For $20MHz \le f_{Nom} < 50MHz$: For $50MHz \le f_{Nom} \le 100MHz$:	- -	20 25 30	mA
Output Waveform (AHCMOS and ACMOS)	-	ESCC No. 24200		Square	etrical Wave te 2)	-
Output Voltage High Level Variants 01 to 06: Variants 07 to 12:	V _{ОН}	ESCC No. 24200		2.4 4.5	-	٧
Output Voltage Low Level Variants 01 to 06: Variants 07 to 12:	Vol	ESCC No. 24200			0.4 0.5	V
Frequency Accuracy	$\Delta f/f_{Nom}$	ESCC No. 24200	At T _{amb} = +25 ±1°C Referred to f _{Nom}	ı	±25	ppm
Frequency-Voltage Tolerance Variants 01 to 06: Variants 07 to 12:	Δf/f(V)	ESCC No. 24200	At T _{amb} = +25 ±1°C Referred to f at V _{CCNom} For 2.97V, 3.3V & 3.63V: For 4.5V, 5V & 5.5V:	-	±3 ±3	ppm
Frequency-Load Tolerance	Δf/f(L)	ESCC No. 24200	At T _{amb} = +25 ±1°C	-	±5	ppm
Startup Time	t _{su}	ESCC No. 24200		-	10	ms
Rise Time	t _r	ESCC No. 24200	For 4MHz ≤ f _{Nom} < 16MHz: For 16MHz ≤ f _{Nom} ≤ 100MHz:	-	10 7	ns
Fall Time	t _f	ESCC No. 24200	For 4MHz ≤ f _{Nom} < 16MHz: For 16MHz ≤ f _{Nom} ≤ 100MHz:		10 7	ns
Duty Cycle	DC	ESCC No. 24200		45	55	%
Ageing Analysis	Δf/f	ESCC No. 3503	Note 3 Ageing Period = 1 year Ageing Period = 18 years	-	±5 ±15	ppm



2.3.2 <u>High and Low Temperatures Electrical Measurements</u>

Characteristics Symbols Test		Test Conditions	Lin	nits	Units	
		Method	Note 1	Min	Max	
Input Current	I _{IN}	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C			mA
			For 4MHz ≤ f _{Nom} < 20MHz:	-	20	
			For $20MHz \le f_{Nom} < 50MHz$:	-	25	
			For $50MHz \le f_{Nom} \le 100MHz$:	-	30	
Output Waveform	-	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C	Symm Square		ı
Output Voltage High Level	Vон	ESCC	At T _{amb} = -55 (+5 -0)°C and			V
Variants 01 to 06:		No. 24200	+110 (+0 -5)°C	2.4	-	
Variants 07 to 12:				4.5	-	
Output Voltage Low Level	V _{OL}	ESCC	At T _{amb} = -55 (+5 -0)°C and			V
Variants 01 to 06:		No. 24200	+110 (+0 -5)°C	-	0.4	
Variants 07 to 12:				-	0.5	
Frequency-Temperature Stability	Δf/f(T)	ESCC No. 24200	At T _{amb} = -55 (+1 -0)°C to +110 (+0 -1)°C. Note 4	-	±30	ppm
			Referred to f at T _{amb} = +25 ±1°C			
Frequency-Voltage Tolerance	Δf/f(V)	ESCC No. 24200	At T _{amb} = -55 (+1 -0)°C to +110 (+0 -1)°C			ppm
			Referred to f at V _{CCNom}			
Variants 01 to 06:			For 2.97V, 3.3V & 3.63V:	-	±3	
Variants 07 to 12:			For 4.5V, 5V & 5.5V:	-	±3	
Startup Time	t _{su}	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C		10	ms
Rise Time	t _r	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C			ns
			For 4MHz ≤ f _{Nom} < 16MHz:	-	10	
			For $16MHz \le f_{Nom} \le 100MHz$:	-	7	
Fall Time	t _f	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C			ns
			For 4MHz ≤ f _{Nom} < 16MHz:	-	10	
			For $16MHz \le f_{Nom} \le 100MHz$:	-	7	
Duty Cycle	DC	ESCC No. 24200	At T _{amb} = -55 (+5 -0)°C and +110 (+0 -5)°C	45	55	%

2.3.3 Notes to Paras. 2.3.1 and 2.3.2 Room, High and Low Electrical Measurements

- 1. Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3°C and the component under test shall be operated at V_{CCNom} with an output load of C_{LNom} in parallel with R_L = 1k Ω . V_{CCNom} and C_{LNom} are specified in Para. 1.5 Maximum Ratings.
- 2. The shape of the output waveform shall comform to the requirements specified in the Manufacturer's PID, as applicable for AHCMOS or ACMOS (see Para. 1.4.2(b)).
- 3. All measurements aquired during Frequency Ageing shall be taken into account when performing Ageing Analysis.
- 4. Frequency-Temperature Stability shall be measured at a minimum of 10 equally spaced increments over the specified temperature range.



2.4 PARAMETER DRIFT VALUES

Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3°C.

The test methods and test conditions shall be as per the corresponding test defined in Para. 2.3.1 Room Temperature Electrical Measurements.

The drift values (Δ) shall not be exceeded for each characteristic specified. The corresponding absolute limit values for each characteristic shall not be exceeded.

Characteristics	Symbols		Limits		Units
		Drift	Abso	olute	
		Value Δ	Min	Max	
Input Current	I _{IN}				mA
For 4MHz ≤ f _{Nom} < 20MHz:		±5%	-	20	
For 20MHz \leq f _{Nom} $<$ 50MHz:		±5%	-	25	
For $50MHz \le f_{Nom} \le 100MHz$:		±5%	-	30	
Frequency Accuracy	$\Delta f/f_{Nom}$	±10			ppm
Initial measurement:			-	±15	
Final measurement:			-	±25	



2.5 <u>INTERMEDIATE AND END-POINT ELECTRICAL MEASUREMENTS</u>

Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3 °C.

The test methods and test conditions shall be as per the corresponding test defined in Para. 2.3.1 Room Temperature Electrical Measurements or Para. 2.3.2 High and Low Temperatures Electrical Measurements, as follows.

The drift values (Δ) shall not be exceeded for each characteristic specified. Unless otherwise specified, the corresponding absolute limit values for each characteristic shall not be exceeded.

Characteristics	Symbols	Test		Limits		Units
		Conditions	Drift			
			Value Δ	Min	Max	
Input Current	I _{IN}	As per				mΑ
For $4MHz \le f_{Nom} < 20MHz$:		Para. 2.3.1	-	-	20	
For $20MHz \le f_{Nom} < 50MHz$:			-	-	25	
For $50MHz \le f_{Nom} \le 100MHz$:			-	-	30	
Output Waveform	-	As per Para. 2.3.1	-		netrical e Wave	ı
Output Voltage High Level	Voh	As per				V
Variants 01 to 06:		Para. 2.3.1	-	2.4	-	
Variants 07 to 12:			-	4.5	-	
Output Voltage Low Level	V _{OL}	As per				V
Variants 01 to 06:		Para. 2.3.1	-	-	0.4	
Variants 07 to 12:			-	-	0.5	
Frequency Accuracy	$\Delta f/f_{Nom}$	As per Para. 2.3.1	±8.5 (1)	-	±25 (2)	ppm
Frequency-Temperature Stability	Δf/f(T)	As per Para. 2.3.1		ı	±30	ppm
Rise Time	tr	As per				ns
For $4MHz \le f_{Nom} < 16MHz$:		Para. 2.3.1	-	-	10	
For $16MHz \le f_{Nom} \le 100MHz$:			-	-	7	
Fall Time	t _r	As per				ns
For 4MHz ≤ f _{Nom} < 16MHz:		Para. 2.3.1	-	-	10	
For $16MHz \le f_{Nom} \le 100MHz$:			-	-	7	
Duty Cycle	DC	As per Para. 2.3.1	-	45	55	%

NOTES:

- 1. Drift value (Δ) is only applicable to testing during the Endurance Subgroup.
- 2. Absolute limit is only applicable to testing during the Environmental/Mechanical Subgroup.

2.6 <u>BURN-IN CONDITIONS</u>

The test conditions for Burn-in, tested as specified in the ESCC Generic Specification, shall be as follows:

(a) Ouptut Load: C_{LNom} in parallel with $R_L = 1k\Omega$. C_{LNom} is specified in Para. 1.5 Maximum Ratings.



2.7 FREQUENCY AGEING CONDITIONS

The test conditions for Frequency Ageing, tested as specified in the ESCC Generic Specification, shall be as follows:

(a) Ouptut Load: C_{LNom} in parallel with $R_L = 1k\Omega$. C_{LNom} is specified in Para. 1.5 Maximum Ratings.

2.8 OPERATING LIFE CONDITIONS

The test conditions for Operating Life, tested as specified in the ESCC Generic Specification, shall be as follows:

(a) Ouptut Load: C_{LNom} in parallel with $R_L = 1k\Omega$. C_{LNom} is specified in Para. 1.5 Maximum Ratings.

2.9 TOTAL DOSE RADIATION TESTING

All lots shall be irradiated in accordance with ESCC Basic Specification No. 22900, low dose rate (window 2: 36rad(Si) to 360rad(Si) per hour).

2.9.1 Bias Conditions and Total Dose Level for Total Dose Radiation Testing

The following bias condition (worst-case) shall be used for Total Dose Radiation Testing at T_{amb} = +22 ±3°C:

With Supply Voltage:

- Variants 01 to 06: $V_{CC} = 3.63V$ during irradiation.
- Variants 07 to 12: $V_{CC} = 5.5V$ during irradiation.

The total dose level applied shall be as specified in Para. 1.4.3 or in the Purchase Order.



2.9.2 <u>Electrical Measurements for Total Dose Radiation Testing</u>

Prior to irradiation testing the devices shall have successfully met Para. 2.3.1 Room Temperature Electrical Measurements specified herein.

Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3°C.

Unless otherwise specified, the test methods and test conditions shall be as per the corresponding test defined in Para. 2.3.1 Room Temperature Electrical Measurements.

The parameters to be measured during irradiation testing, on completion of irradiation testing, after 24 hours anneal at Room Temperature and after 168 hours anneal at T_{amb} = +100 ±3°C are shown below.

Characteristics	Symbols	Lin	nits	Units
		Abso	olute	
		Min	Max	
Input Current	I _{IN}			mA
For $4MHz \le f_{Nom} < 20MHz$:		-	20	
For $20MHz \le f_{Nom} < 50MHz$:		-	25	
For $50MHz \le f_{Nom} \le 100MHz$:		-	30	
Output Waveform	-		etrical Wave	-
Output Voltage High Level	Vон	'		V
Variants 01 to 06:	3.1	2.4	-	
Variants 07 to 12:		4.5	-	
Output Voltage Low Level	V _{OL}			V
Variants 01 to 06:		-	0.4	
Variants 07 to 12:		-	0.5	
Frequency Accuracy	$\Delta f/f_{Nom}$	-	±25	ppm
Rise Time	t _r			ns
For 4MHz ≤ f _{Nom} < 16MHz:		-	10	
For $16MHz \le f_{Nom} \le 100MHz$:		-	7	
Fall Time	t _f			ns
For 4MHz ≤ f _{Nom} < 16MHz:		-	10	
For $16MHz \le f_{Nom} \le 100MHz$:		-	7	
Duty Cycle	DC	45	55	%



APPENDIX A AGREED DEVIATIONS FOR RAKON FRANCE S.A.S. (F)

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 1.4.3 Component Type Variants	Oscillators with ACMOS outputs (output waveform code AC) are available from Rakon but only with specific frequencies. Customers should contact Rakon to confirm feasibility and availability.
Para. 2.1.2 Deviations from the Generic Specification: Deviations from Screening Tests - Chart F3	Solderability: Solderability during Chart F3 Screening Tests shall only be performed once for each package batch/lot used to manufacture oscillators, on 3 components from the first respective oscillator procurement lot. Solderability may be performed in accordance with Test Ta (without ageing) of IEC Publication No. 60068-2-20. Note: Solderability during Chart F4 Qualification and Periodic Testing still applies.
Para. 2.1.2.1 Deviations from Qualification and Periodic Tests - Chart F4	Solderability: Solderability may be performed in accordance with Test Ta (without ageing) of IEC Publication No. 60068-2-20.